A novel nitrogen-doped carbon-coated SnSe₂ based on post-synthetic modified MOF as high-performance anode materials for LIBs and SIBs

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Fig. S1 The SEM images of SnSe₂/C-N after 100 cycles of charge/discharge in LIBs.



Fig. S2 EDS mapping images for $SnSe_2/C-N$: (a) HAADF image; (b) all elements labeled image; and (c) all elements' EDS spectra.



Fig. S3 Comparison of FT-IR of $SnSe_2/C$ and $SnSe_2/C$ -N.



Fig. S4 The XPS spectra of the SnSe₂/C-N composite.



Fig. S5 Thermogravimetric analysis patterns of $SnSe_2/C$ and $SnSe_2/C-N$.



Fig. S6 EIS of $SnSe_2/C$ and $SnSe_2/C$ -N electrodes for LIBs.



Fig. S7 (a) CV curves of $SnSe_2/C$ for different scan rates (0.2-1.0 mV s⁻¹), (b) log (scan rate) /log (current) plots, (c) Contribution of pseudocapacitive (orange area) at 0.6 mV s⁻¹, and (d) Histogram of the pseudocapacitive contributions at different scan rates.